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Date Searched: 6/18/2002

Databases Searched: USPAT, USPGPUB

Plurals: ON

Terms Searched:

L1 716/\$.ccls. and (self adj heat\$3)

Results: 4 hits

L2 (((716/\$.ccls.or 257/758.ccls or 438/637.ccls.) and (reliability or electromigrat\$4 or electro-migrat\$4 or self-heat\$4)) and (layout or placement or floorplan\$4 or floor-plan\$4)) and (overlap\$4 same row) and @pd>20010910

Resultss: 0 hit

L3 (signal same (integrity or reliability)) and (electromigrat\$4 or (self adj heat\$4) or (hot adj electron)) and (716/\$.ccls.or 257/758.ccls or 438/637.ccls.) and @pd>20010910

Results: 3 hits

US 6308303 B1 USPAT Mysore, Sriram et al. 716/5

US 6308302 B1 USPAT Hathaway, David James et al. 716/5

Database Searched: IEEE/IEEE

Terms Searched: microprocessor and (elctromigration or (self <near/2> heat\*))

Results: Your search matched 3 of 775001 documents.

Date Searched: 9/17/2001

Database Searched: USPAT

Plurals: ON

Terms Searched:

L1 transistor same folding

L2 electromigrat\$4 or (electro adj migrat\$4)

L3 1 and 2

Results: 1 hit

L4 1 and 716/\$.ccls.

Results: 20 hits

L5 signal same (reliability or integrity)

L6 1 and 5

Results: 6 hits

US 5751180 A USPAT D'Addeo, Michael Lee 327/379

US 6163877 A USPAT Gupta, Avaneendra 716/8

US 6077308 A USPAT Carter, Craig A. , et al. 716/8

US 5995734 A USPAT Saika, Shunji 716/9

US 5737236 A USPAT Maziasz, Robert , et al. 716/8

US 5675501 A USPAT Aoki, Sachiko 716/8

Databases Searched: EPO, JPO, IBM TDB, DERWENT

Plurals: ON

Terms Searched:

L1 transistor same folding

L2 electromigrat\$4 or (electro adj migrat\$4)

L3 1 and 2

Results: 0 hits

L4 signal same (reliability or integrity)

L5 1 and 4

Results: 2 hits

JP 60197034 A A JPO YAMAMOTO, YOSHINOBU , CHIBA, TAKASHI , et al.

Date Searched: 9/10/2001

Database Searched: USPAT

Plurals: ON

Terms Searched:

L1 716/\$.ccls.

L2 (reliability or electromigrat\$4 or electro-migrat\$4 or self-heat\$4)

L3 layout or placement or floorplan\$4 or floor-plan\$4

L4 1 and 2 and 3

Results: 214 hits

L5 (electromigrat\$4 or electro-migrat\$4) and self-heat\$4

L6 1 and 3 and 5

Results: 0 hits

L7 overlap\$4 same row

L8 4 and 7

Results: 6 hits

L9 signal same (integrity or reliability)

L10 electromigrat\$4 or (self adj heat\$4) or (hot adj electron)

L11 1 and 9 and 10

Results: 4 hits

Databases Searched: EPO, JPO, IBM TDB, DERWENT

Plurals: ON

Terms Searched:

L1 (signal or constraint or cost) same (integrity or reliability)

L2 layout or placement or floorplan\$4 or floor-plan\$4

L3 1 and 2

Results: 248 hits

L4 electromigrat\$4 or (self adj heat\$4) or (hot adj electron)

L5 3 and 4

Results: 1 hits

L6 1 and 4

Results: 40 hits

US 6002857 A USPAT Ramachandran, Venkateswaran ("Venky") 716/14

US 5984510 A USPAT Guruswamy, Mohan , et al. 716/2

US 6286128 B1 USPAT Pileggi, Lawrence , et al. 716/18

US 6038383 A USPAT Young, Duane J. , et al. 716/5

US 6253361 B1 USPAT Buch, Premal 716/6

US 5737580 A USPAT Hathaway, David James , et al. 716/12

US 6195787 B1 USPAT Yokoyama, Moto 716/8

US 5822218 A USPAT Moosa, Mohamed S. , et al. 716/4

US 5648910 A USPAT Ito, Soichi 716/2

JP 2000206201 A A JPO FURUE, KATSUYA

JP 08293532 A A JPO NISHIMURA, KOICHI

JP 06302703 A A JPO YAMADA, TATSUYA , KATO, YOSHIKI

JP 03149823 A A JPO MATSUOKA, FUMITOSHI

US 6242807 B1 USPAT Kazami, Tetsuo 257/758

Database Searched: IEE/IEEE

Terms Searched: (signal or constraint or cost) and (integrity or reliability) and (layout or placement or floorplan\* or floor-plan\*) and (electromigrat\* or (self <near/2> heat\*))

Results: Your search matched 4 of 713260 documents.

Terms Searched: (integrity or reliability) and (layout or placement or floorplan\* or floor-plan\*) and (electromigrat\* or (self <near/2> heat\*))

Results: Your search matched 19 of 713260 documents.

Terms Searched: (transistor <near/4> folding) and (signal <near/10> (reliability or integrity))

Results: Your search matched [0] of [714343] documents.

Terms Searched: (transistor <near/4> folding)

Results: Your search matched 24 of 714315 documents.

Date Searched: 9/17/2001  
Database Searched: USPAT  
Plurals: ON

Terms Searched:

L1 transistor same folding  
L2 electromigrat\$4 or (electro adj migrat\$4)  
L3 1 and 2  
Results: 1 hit  
L4 1 and 716/\$.ccls.  
Results: 20 hits  
L5 signal same (reliability or integrity)  
L6 1 and 5  
Results: 6 hits

US 5751180 A USPAT D'Addeo, Michael Lee 327/379

upta, A.; Siang-Chun The; Hayes, J.P. "XPRESS: A Cell Layout Generator with Integrated Transistor Folding ", European Design and Test Conference, 1996.

ED&TC96. Proceedings, 1996, pp. 393-400.\*

US 6163877 A	USPAT Gupta, Avaneendra	716/8
US 6077308 A	USPAT Carter, Craig A. , et al.	716/8
US 5995734 A	USPAT Saika, Shunji	716/9
US 5737236 A	USPAT Maziasz, Robert , et al.	716/8
US 5675501 A	USPAT Aoki, Sachiko	716/8

Databases Searched: EPO, JPO, IBM TDB, DERWENT

Plurals: ON

Terms Searched:

L1 transistor same folding  
L2 electromigrat\$4 or (electro adj migrat\$4)  
L3 1 and 2  
Results: 0 hits  
L4 signal same (reliability or integrity)  
L5 1 and 4  
Results: 2 hits

JP 60197034 A A JPO YAMAMOTO, YOSHINOBU , CHIBA, TAKASHI , et al.

Date Searched: 9/10/2001  
Database Searched: USPAT  
Plurals: ON

Terms Searched:

L1 716/\$.ccls.  
L2 (reliability or electromigrat\$4 or electro-migrat\$4 or self-heat\$4)  
L3 layout or placement or floorplan\$4 or floor-plan\$4  
L4 1 and 2 and 3  
Results: 214 hits  
L5 (electromigrat\$4 or electro-migrat\$4) and self-heat\$4  
L6 1 and 3 and 5  
Results: 0 hits  
L7 overlap\$4 same row  
L8 4 and 7  
Results: 6 hits

L9 signal same (integrity or reliability)  
 L10 electromigrat\$4 or (self adj heat\$4) or (hot adj electron)  
 L11 1 and 9 and 10  
 Results: 4 hits

Databases Searched: EPO, JPO, IBM TDB, DERWENT

Plurals: ON

Terms Searched:

L1 (signal or constraint or cost) same (integrity or reliability)

L2 layout or placement or floorplan\$4 or floor-plan\$4

L3 1 and 2

Results: 248 hits

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L5 3 and 4

Results: 1 hits

L6 1 and 4

Results: 40 hits

US 6002857 A	USPAT Ramachandran, Venkateswaran ("Venky")	716/14
US 5984510 A	USPAT Guruswamy, Mohan , et al.	716/2
US 6286128 B1	USPAT Pileggi, Lawrence , et al.	716/18
US 6038383 A	USPAT Young, Duane J. , et al.	716/5
US 6253361 B1	USPAT Buch, Premal	716/6
US 5737580 A	USPAT Hathaway, David James , et al.	716/12
US 6195787 B1	USPAT Yokoyama, Moto	716/8
US 5822218 A	USPAT Moosa, Mohamed S. , et al.	716/4
US 5648910 A	USPAT Ito, Soichi	716/2
JP 2000206201 A	A JPO FURUE, KATSUYA	
JP 08293532 A A	JPO NISHIMURA, KOICHI	
JP 06302703 A A	JPO YAMADA, TATSUYA , KATO, YOSHIAKI	
JP 03149823 A A	JPO MATSUOKA, FUMITOSHI	
US 6242807 B1	USPAT Kazami, Tetsuo	257/758
US 5817574 A	USPAT Gardner, Donald S.	438/637

Database Searched: IEE/IEEE

Terms Searched: (signal or constraint or cost) and (integrity or reliability) and (layout or placement or floorplan\* or floor-plan\*) and (electromigrat\* or (self <near/2> heat\*))

Results: Your search matched 4 of 713260 documents.

Terms Searched: (integrity or reliability) and (layout or placement or floorplan\* or floor-plan\*) and (electromigrat\* or (self <near/2> heat\*))

Results: Your search matched 19 of 713260 documents.

Terms Searched: (transistor <near/4> folding) and (signal <near/10> (reliability or integrity))

Results: Your search matched [0] of [714343] documents.

Terms Searched: (transistor <near/4> folding)

Results: Your search matched 24 of 714315 documents.